Notice of References Cited Application/Control No. 10/664,660 Examiner Christopher R Nalevanko Applicant(s)/Patent Under Reexamination LEE ET AL. Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| | Α | US-2004/0133909 | 07-2004 | Ma, Yue | 725/034 |
| | В | US-2003/0226141 | 12-2003 | Krasnow et al. | 725/9 |
| | С | US-6,029,045 | 02-2000 | Picco et al. | 725/34 |
| | D | US-6,182,050 | 01-2001 | Ballard, Clinton L. | 705/14 |
| | E | US-2003/0023973 | 01-2003 | Monson et al. | 725/34 |
| | F | US-5,532,735 | 07-1996 | Blahut et al. | 725/32 |
| | G | US-2002/0178445 | 11-2002 | Eldering et al. | 725/32 |
| | Н | US-2003/0018969 | 01-2003 | Humpleman et al. | 725/34 |
| | ı | US-2004/0078809 | 04-2004 | Drazin, Jonathan | 725/034 |
| | J | US-6,177,931 | 01-2001 | Alexander et al. | 725/52 |
| | K | US-5,774,170 | 06-1998 | Hite et al. | 725/34 |
| | L | US-6,141,010 | 10-2000 | Hoyle, Martin David | 715/854 |
| ٦ | М | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | Ν | | | | | |
| | 0 | | | | | |
| | Р | | | | | |
| | Ö | | | | | |
| | R | | | | | |
| | s | | | | | |
| | Т | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | ٧ | · |
| | W | |
| | x | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.